


<b>Search Notes</b>  	<b>Application/Control No.</b>  10615840	<b>Applicant(s)/Patent Under Reexamination</b>  KIM ET AL.
	<b>Examiner</b>  DAVID Y CHUNG	<b>Art Unit</b>  2871

SEARCHED			
Class	Subclass	Date	Examiner
349	38,39,42-44	3/17/08	/D.C./
438	30,149	3/17/08	/D.C./
430	20	3/17/08	/D.C./
257	59,72	3/17/08	/D.C./

SEARCH NOTES		
Search Notes	Date	Examiner
EAST search report	3/17/08	/D.C./
EAST search report	9/12/08	/D.C./

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
same	same	3/30/09	/D.C./

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